

Notice of References Cited	Application/Control No. 10/561,665		Applicant(s)/Patent Under Reexamination AWAZU ET AL.	
	Examiner DANIELLE HENKEL		Art Unit 4112	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,919,157 A	11-1975	Ide et al.	524/269
*	B	US-6,153,073 A	11-2000	Dubrow et al.	204/453
*	C	US-6,274,337 B1	08-2001	Parce et al.	435/29
*	D	US-6,274,089 B1	08-2001	Chow et al.	422/101
*	E	US-6,361,958 B1	03-2002	Shieh et al.	435/7.1
*	F	US-2002/0122747 A1	09-2002	Zhao et al.	422/99
*	G	US-6,472,065 B1	10-2002	Alahapperuma et al.	428/343
*	H	US-6,900,021 B1	05-2005	Harrison et al.	435/7.21
*	I	US-7,041,509 B2	05-2006	Parce et al.	436/514
*	J	US-7,138,269 B2	11-2006	Blankenstein, Gert	435/287.2
*	K	US-7,201,873 B2	04-2007	Tanaka et al.	422/58
*	L	US-7,276,170	10-2007	Oakey et al.	210/767
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 9903684 A2	01-1999	World Intellect	YON-HIN et al.	B41M 01/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.